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Strained Induced Local Distortions of $\text{Nd}_{0.5}\text{Sr}_{0.5}\text{MnO}_3$ films

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Beamline(s): X16C

Introduction: Magnetotransport properties of thin films are augmented by thickness dependent strain due to substrate-film mismatch [1, 2, 3]. Prellier et al has found a thickness induced metallic state of $\text{Nd}_{0.5}\text{Sr}_{0.5}\text{MnO}_3$ films at $\sim 150\text{K}$, while thinner films are found to be insulating as in bulk [4]. The local structural details as studied by polarized Mn-K edge absorption spectra of $\text{Nd}_{0.5}\text{Sr}_{0.5}\text{MnO}_3$ films of 500\AA , 1000\AA , and 2000\AA thickness reveal a preferential orientation of the e_g orbitals out of plane for the thinnest film. The thicker films show lesser anisotropy of orientation [5]. The local structure about the Sr atoms would be of crucial importance in understanding the order of the lattice as depending on thickness.

Methods and Materials: Epitaxial $\text{Nd}_{0.5}\text{Sr}_{0.5}\text{MnO}_3$ films (202) of 500\AA , 1000\AA , and 2000\AA thickness were deposited on LaAlO_3 (100) substrates via the pulsed laser deposition technique. An extended x-ray absorption fine-structure study was conducted at the Sr K-edge.

Results: Figure 1 depicts the fourier transforms of $\chi(k)*k^3$ of these films and that of bulk. There is an increased local distortion in the Sr-O shell for the 500\AA film, whereas the 1000\AA and 2000\AA films track the bulk data. However, previous measurements have found that in-plane strain persists in the 1000\AA and 2000\AA thick films, which prevents the transition from metallic to insulating phase as seen in bulk [5].

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References:

[1] S. Jin, T. H. Tiefel, M. McCormack, H. M. O'Bryan, L. H. Chen, R. Ramesh, and D. Schurig, Appl. Phys. Lett. **67**, 557 (1995).

[2] M. G. Blamire, B.-S. Teo, J. H. Durrell, N. D. Mathur, Z. H. Barber, J. L. McManus Driscoll, L. F. Cohen, and J. E. Evetts, J. Magn. Magn. Mater. **191**, 359 (1999).

[3] J. Z. Sun, D. W. Abraham, R. A. Rao, and C. B. Eom, Appl. Phys. Lett. **74**, 3017 (1999).

[4] W. Prellier, A. Biswas, M. Rajeswari, T. Venkatesan, and R. L. Greene, Appl. Phys. Lett. **75**, 397 (1999).

[5] Q. Qian, T. A. Tyson, C.-C. Kao, W. Prellier, J. Bai, A. Biswas, and R. L. Greene, Phys. Rev. B **63**, 224424 (2001)

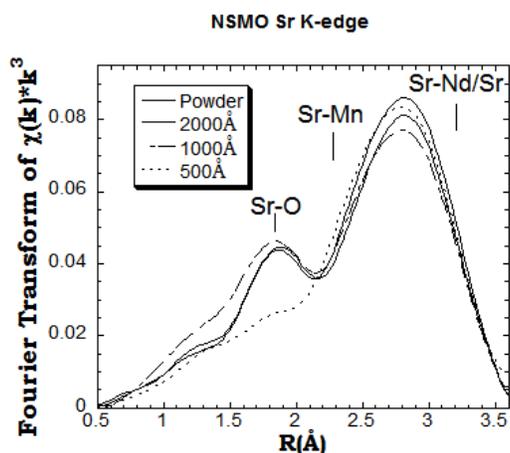


Figure 1. The local distortions manifested, as the small Sr-O peak, is consistent with the high resistivity [insulating phase] observed in the 500\AA film compared to the 1000\AA and 2000\AA films.